



ANNEX E

SYSTEM PERFORMANCE CHECK PLOTS



Measurement Report for Device, , , CW, Channel 0 (2450.000 MHz)

Device Under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	50.0 x 10.0 x 8.0		Dipole

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	,		CW, 0--	2450.000, 0	7.22	1.78	39.2

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
ELI V8.0 (20deg probe tilt) – SN: 2102	HBBL-600-10000 DAK 3.5 Head 21.6 deg.C 2025-Mar-03 SYS3 B3.prn, 2025-03-04	EX3DV4 – SN7804, 2024-08-14	DAE4ip Sn1786, 2024-08-07

Scans Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	40.0 x 80.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-03-04, 13:34	2025-03-04, 13:41
psSAR1g [W/Kg]	2.40	2.44
psSAR10g [W/Kg]	1.18	1.15
Power Drift [dB]	-0.02	-0.12
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	Positive only	Positive only
M2/M1 [%]		82.3
Dist 3dB Peak [mm]		9.0

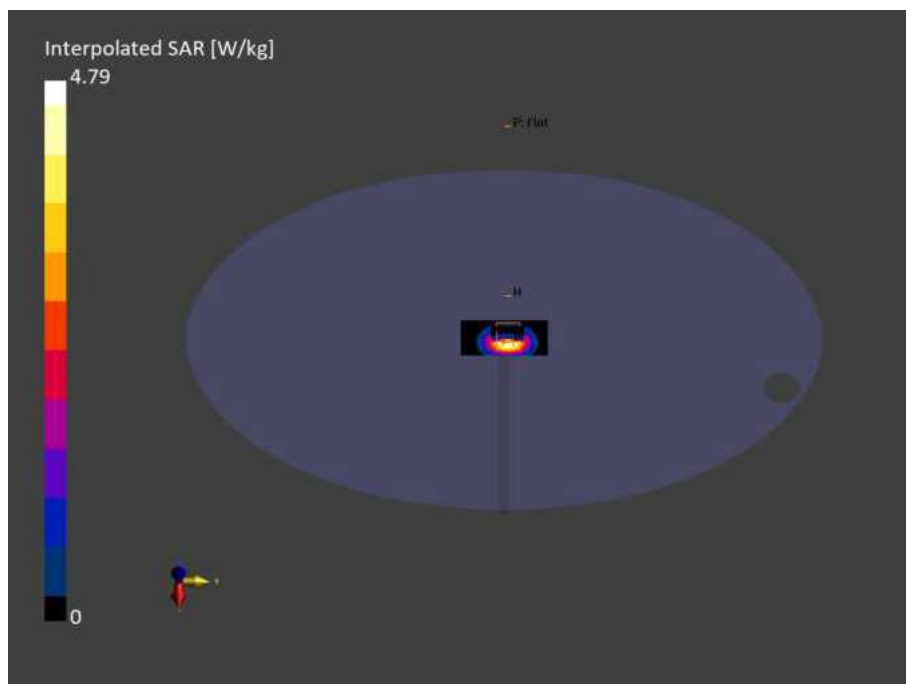


Figure E.1: System performance check results at 2450 MHz



Measurement Report for Device, , , CW, Channel 0 (2450.000 MHz)

Device Under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	50.0 x 10.0 x 8.0		Dipole

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	,		CW, 0--	2450.000, 0	7.22	1.79	39.8

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
ELI V8.0 (20deg probe tilt) – SN: 2102	HBBL-600-10000 DAK 3.5 Head ELI 21.9 deg.C 2025-Mar-05 SYS3 B3.prn, 2025-03-05	EX3DV4 – SN7804, 2024-08-14	DAE4ip Sn1786, 2024-08-07

Scans Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	40.0 x 80.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-03-05, 09:05	2025-03-05, 09:12
psSAR1g [W/Kg]	2.42	2.46
psSAR10g [W/Kg]	1.18	1.16
Power Drift [dB]	-0.01	-0.03
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	Positive only	Positive only
M2/M1 [%]		82.9
Dist 3dB Peak [mm]		9.1

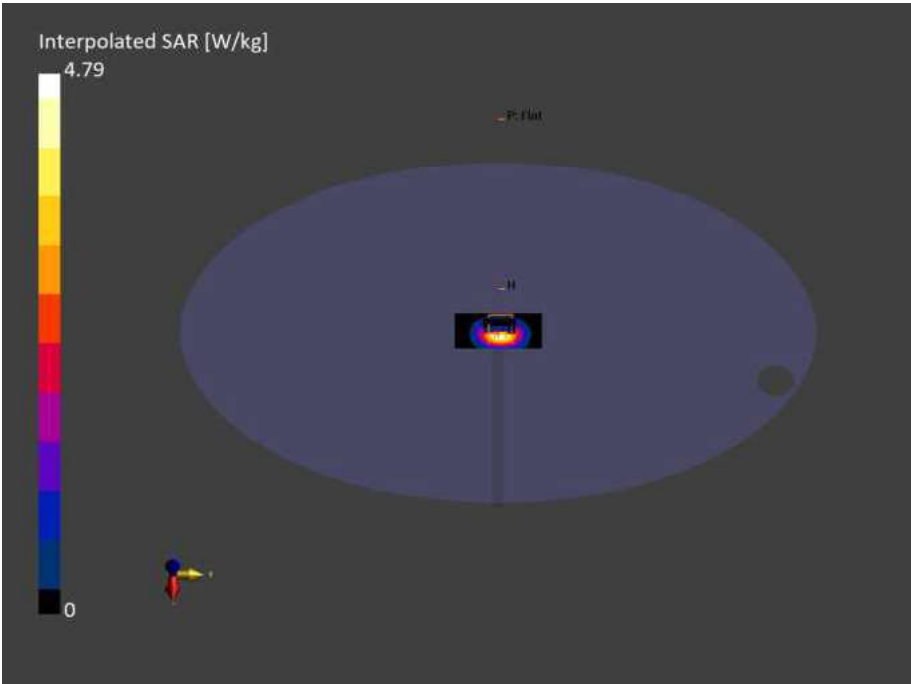


Figure E.2: System performance check results at 2450 MHz



Measurement Report for Device, , , CW, Channel 0 (2450.000 MHz)

Device Under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	50.0 x 10.0 x 8.0		Dipole

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	,		CW, 0--	2450.000, 0	7.22	1.79	39.6

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
ELI V8.0 (20deg probe tilt) – SN: 2102	HBBL-600-10000 DAK 3.5 Head ELI 21.2 deg.C 2025-Mar-10 SYS3 B3.prn, 2025-03-10	EX3DV4 – SN7804, 2024-08-14	DAE4ip Sn1786, 2024-08-07

Scans Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	40.0 x 80.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-03-10, 12:22	2025-03-10, 12:30
psSAR1g [W/Kg]	2.27	2.32
psSAR10g [W/Kg]	1.11	1.09
Power Drift [dB]	-0.01	-0.02
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	Positive only	Positive only
M2/M1 [%]		81.9
Dist 3dB Peak [mm]		9.0

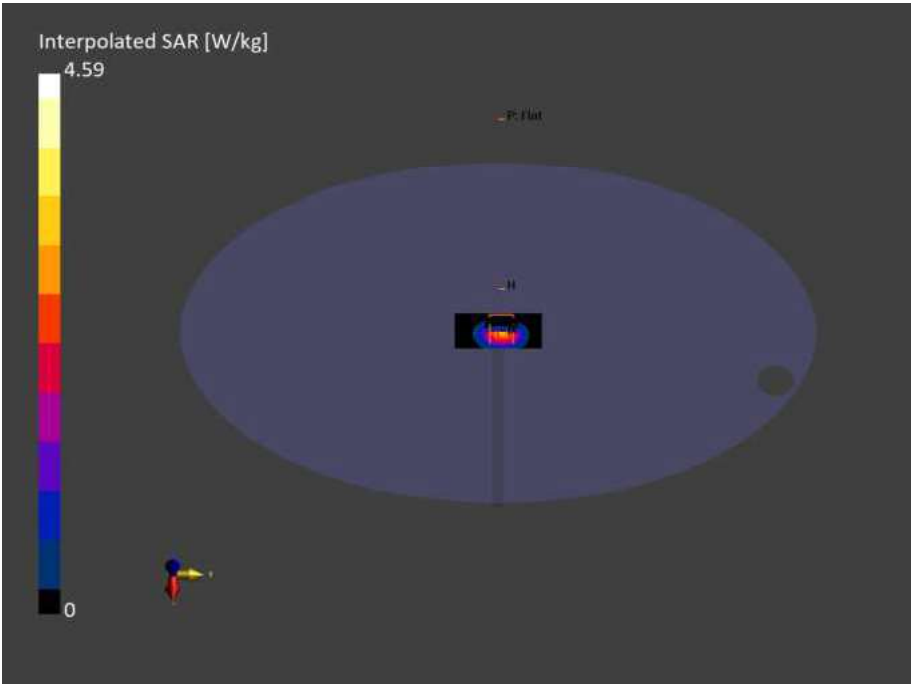


Figure E.3: System performance check results at 2450 MHz



Measurement Report for Device, , , CW, Channel 0 (2450.000 MHz)

Device Under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	50.0 x 10.0 x 8.0		Dipole

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	,		CW, 0--	2450.000, 0	7.22	1.79	39.6

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
ELI V8.0 (20deg probe tilt) – SN: 2102	HBBL-600-10000 DAK 3.5 Head ELI 21.2 deg.C 2025-Mar-10 SYS3 B3.prn, 2025-03-10	EX3DV4 – SN7804, 2024-08-14	DAE4ip Sn1786, 2024-08-07

Scans Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	40.0 x 80.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-03-11, 08:17	2025-03-11, 08:25
psSAR1g [W/Kg]	2.28	2.32
psSAR10g [W/Kg]	1.11	1.09
Power Drift [dB]	-0.00	-0.03
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	Positive only	Positive only
M2/M1 [%]		82.4
Dist 3dB Peak [mm]		9.0

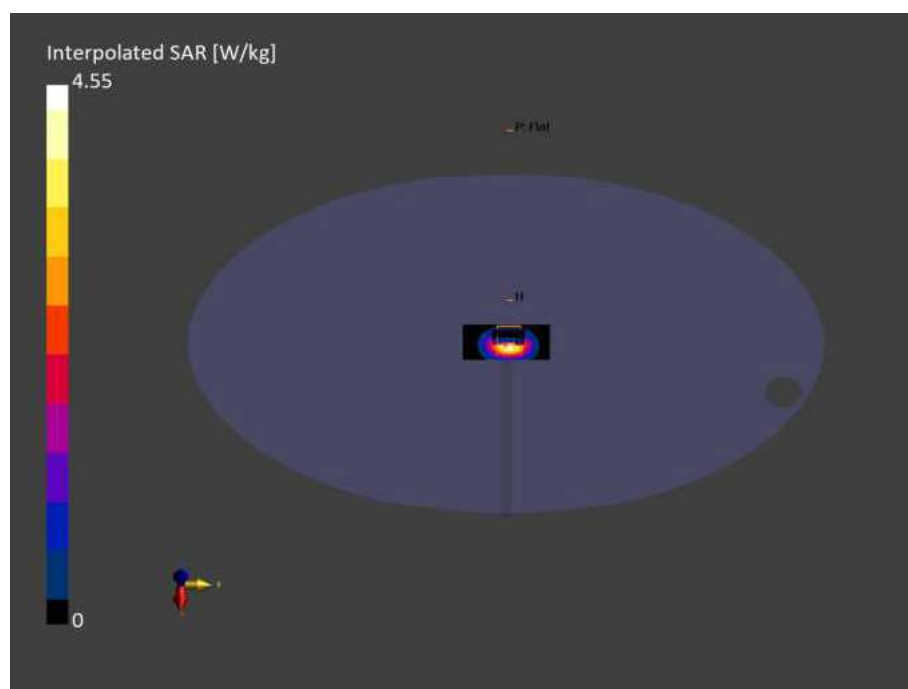


Figure E.4: System performance check results at 2450 MHz



Measurement Report for Device, , , CW, Channel 0 (5200.000 MHz)

Device Under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	50.0 x 10.0 x 8.0		Dipole

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	,		CW, 0--	5200.000, 0	5.45	4.39	35.4

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
ELI V8.0 (20deg probe tilt) – SN: 2102	HBBL-600-10000 DAK 3.5 Head ELI 21.9 deg.C 2025-Mar-05 SYS3 B3.prn, 2025-03-05	EX3DV4 – SN7804, 2024-08-14	DAE4ip Sn1786, 2024-08-07

Scans Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	40.0 x 80.0	22.0 x 22.0 x 22.0
Grid Steps [mm]	10.0 x 10.0	4.0 x 4.0 x 1.4
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.4
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-03-06, 08:57	2025-03-06, 09:04
psSAR1g [W/Kg]	3.29	3.89
psSAR10g [W/Kg]	1.07	1.13
Power Drift [dB]	-0.02	-0.07
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	Positive only	Positive only
M2/M1 [%]		63.4
Dist 3dB Peak [mm]		7.2

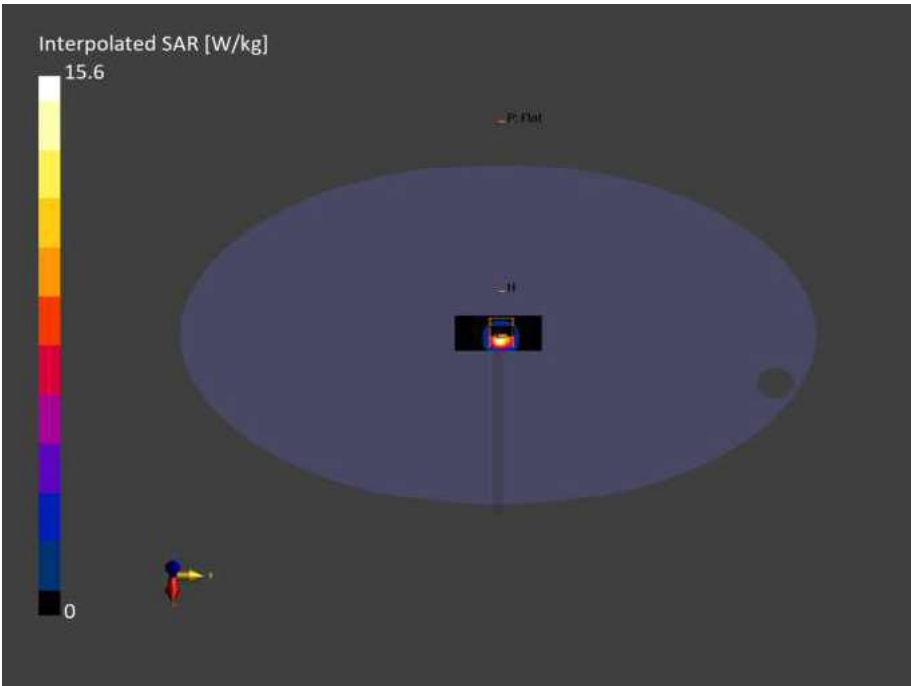


Figure E.5: System performance check results at 5200 MHz



Measurement Report for Device, , , CW, Channel 0 (5200.000 MHz)

Device Under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	50.0 x 10.0 x 8.0		Dipole

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	,		CW, 0--	5200.000, 0	5.45	4.39	35.4

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
ELI V8.0 (20deg probe tilt) – SN: 2102	HBBL-600-10000 DAK 3.5 Head ELI 21.9 deg.C 2025-Mar-05 SYS3 B3.prn, 2025-03-05	EX3DV4 – SN7804, 2024-08-14	DAE4ip Sn1786, 2024-08-07

Scans Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	40.0 x 80.0	22.0 x 22.0 x 22.0
Grid Steps [mm]	10.0 x 10.0	4.0 x 4.0 x 1.4
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.4
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-03-07, 08:55	2025-03-07, 09:03
psSAR1g [W/Kg]	3.32	3.84
psSAR10g [W/Kg]	1.04	1.10
Power Drift [dB]	0.01	-0.00
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	Positive only	Positive only
M2/M1 [%]		63.3
Dist 3dB Peak [mm]		7.2

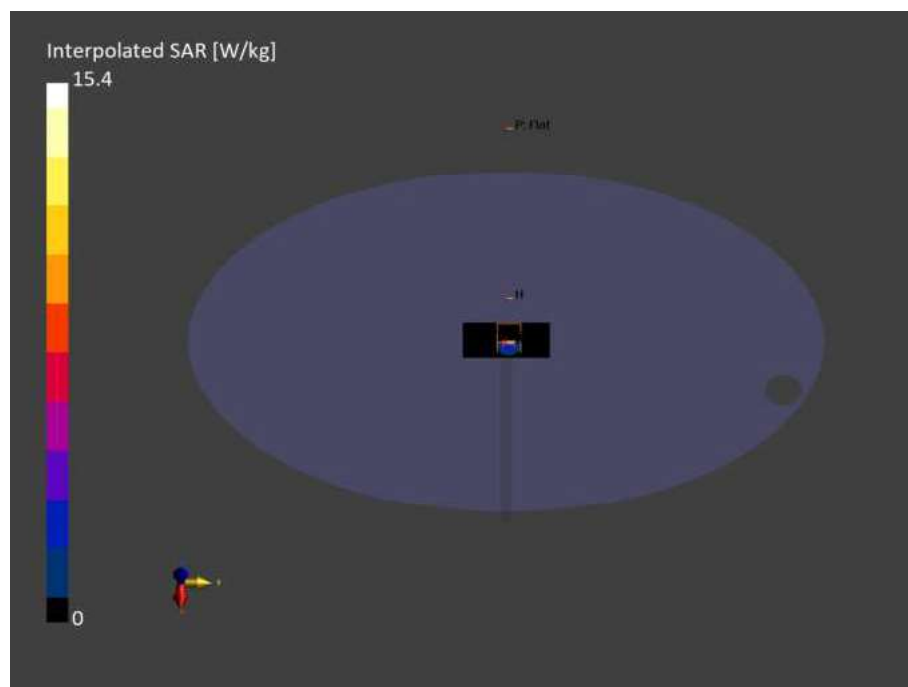


Figure E.6: System performance check results at 5200 MHz



Measurement Report for Device, , , CW, Channel 0 (5200.000 MHz)

Device Under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	50.0 x 10.0 x 8.0		Dipole

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	,		CW, 0--	5200.000, 0	5.45	4.39	35.0

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
ELI V8.0 (20deg probe tilt) – SN: 2102	HBBL-600-10000 DAK 3.5 Head ELI 21.2 deg.C 2025-Mar-10 SYS3 B3.prn, 2025-03-10	EX3DV4 – SN7804, 2024-08-14	DAE4ip Sn1786, 2024-08-07

Scans Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	40.0 x 80.0	22.0 x 22.0 x 22.0
Grid Steps [mm]	10.0 x 10.0	4.0 x 4.0 x 1.4
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.4
MAIA	N/A	N/A
Surface Detection	All points	All points
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-03-10, 08:56	2025-03-10, 09:09
psSAR1g [W/Kg]	3.28	3.85
psSAR10g [W/Kg]	1.04	1.11
Power Drift [dB]	-0.07	-0.13
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	Positive only	Positive only
M2/M1 [%]		63.2
Dist 3dB Peak [mm]		7.4

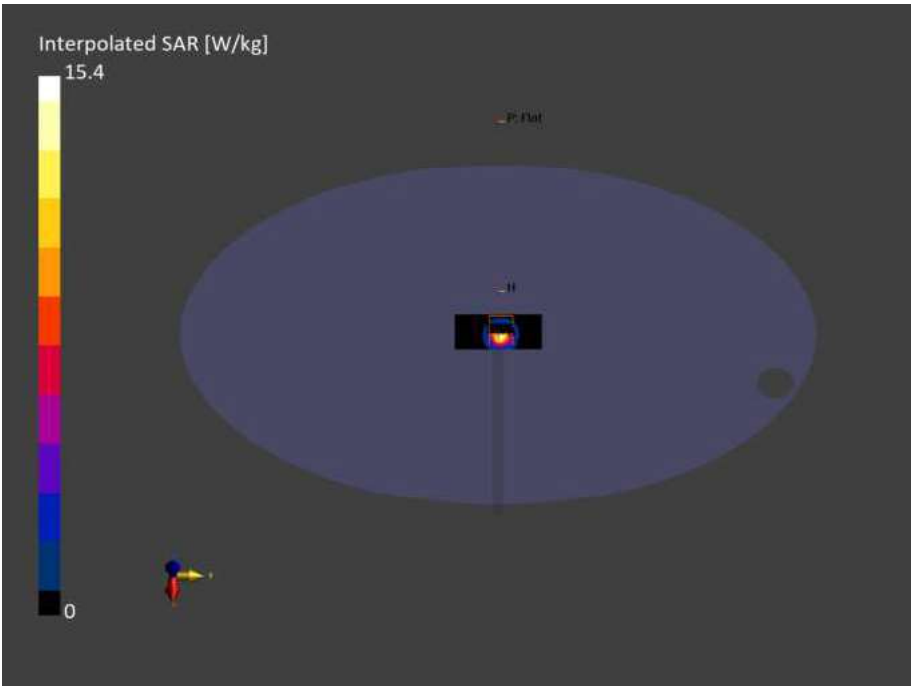


Figure E.7: System performance check results at 5200 MHz